

<b><i>Examiner-Initiated Interview Summary</i></b>	<b>Application No.</b> 10/591,116  <b>Examiner</b> ERIK KASHNIKOW	<b>Applicant(s)</b> THOMASSET, JACQUES  <b>Art Unit</b> 1794
--	---	--

**All Participants:**    **Status of Application:** \_\_\_\_\_  
 (1) ERIK KASHNIKOW.    (3) \_\_\_\_\_.  
 (2) Mr. Duane M. Byers.    (4) \_\_\_\_\_.

**Date of Interview:** 21 January 2008    **Time:** 11:00 AM

**Type of Interview:**  
☒ Telephonic  
☐ Video Conference  
☐ Personal (Copy given to: ☐ Applicant    ☐ Applicant's representative)

Exhibit Shown or Demonstrated: ☐ Yes    ☒ No  
 If Yes, provide a brief description: \_\_\_\_\_

**Part I.**

Rejection(s) discussed:  
n/a

Claims discussed:  
2

Prior art documents discussed:  
n/a

**Part II.**

SUBSTANCE OF INTERVIEW DESCRIBING THE GENERAL NATURE OF WHAT WAS DISCUSSED:  
See Continuation Sheet

**Part III.**

☒ It is not necessary for applicant to provide a separate record of the substance of the interview, since the interview directly resulted in the allowance of the application. The examiner will provide a written summary of the substance of the interview in the Notice of Allowability.  
☐ It is not necessary for applicant to provide a separate record of the substance of the interview, since the interview did not result in resolution of all issues. A brief summary by the examiner appears in Part II above.

/Callie E. Shosho/  
Supervisory Patent Examiner, Art Unit 1794

(Applicant/Applicant's Representative Signature – if appropriate)

Continuation of Substance of Interview including description of the general nature of what was discussed: Examiner called Mr. Byers to discuss an Examiner's Amendment. The result of the conversation was that Examiner and Mr. Byers agreed to amend claim 2, which originally read "[t]he object as claimed in claim 1 wherein a superposition distance is at least equal to the thickness E of the object". The claim will now read "[t]he object as claimed in claim 1 wherein an overlap of the at least two fine functional layers is at least equal to the thickness E of the object".